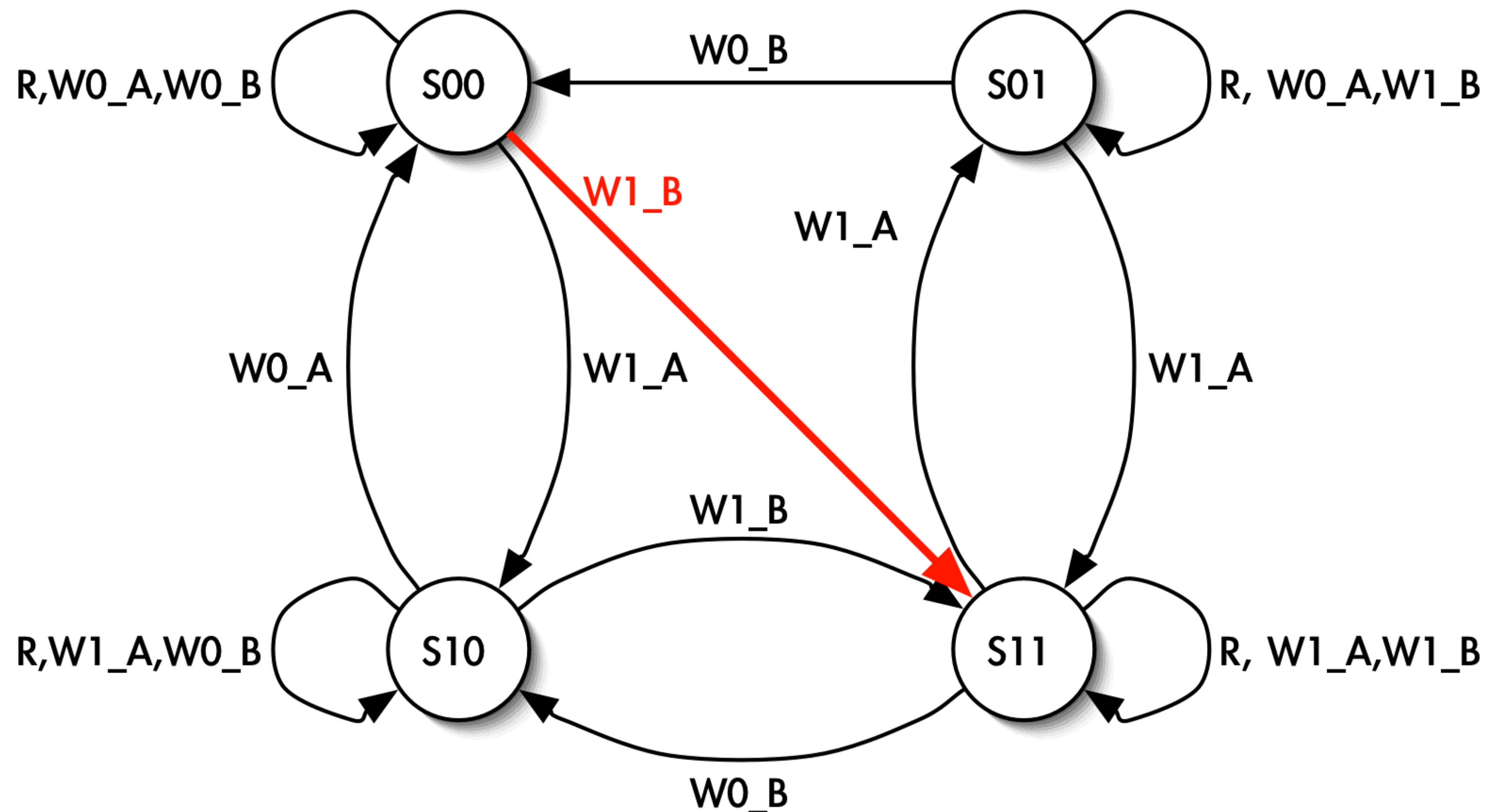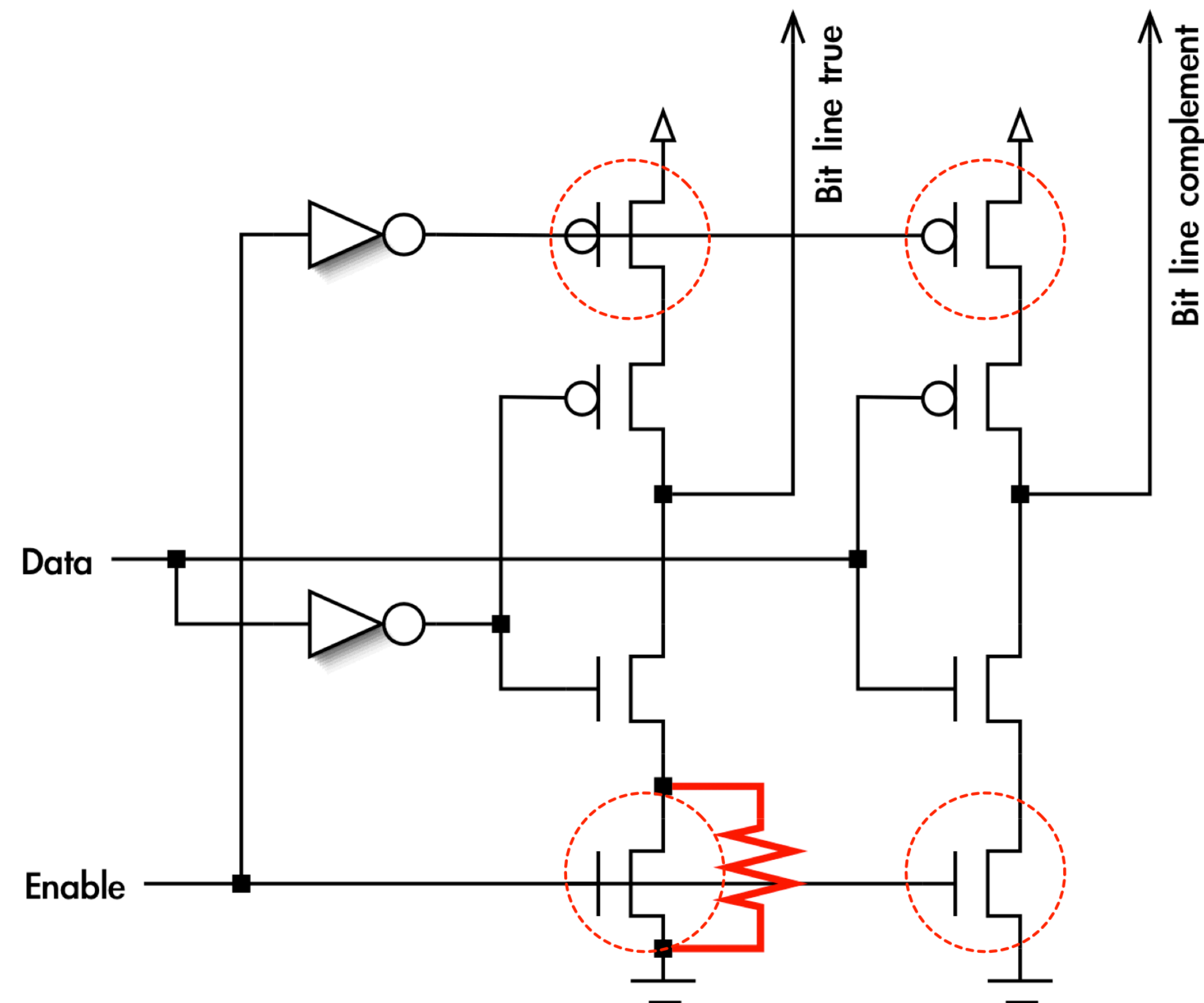Let A and B be two adjacent memory cells. Find one test pattern (that we discussed in the classroom) that detects the following coupling fault. Show how your pattern detects the fault.

HW 03-2 False Write Through

- Advise a test pattern that detects the short faults at the four circled transistors. Show how the faults are detected.

Submission Instructions

- Due date: December 22, 2024

- Submission via NTU Cool.

  - The submitted file must be in pdf format.